ABSTRACT

Methods and systems for improving repairing efficiency in non-volatile memory. Repairing data may be read from an information array associated with the non-volatile memory. The repairing data is generally read to a volatile latch associated with the non-volatile memory. An error correction coding circuit (ECC) circuit can be enabled during reading of the repairing data to thereby identify and repair defective columns or rows associated with the non-volatile memory, regardless of the corruption of the columns.